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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/773,685	WEIMER ET AL.	
Examiner	Art Unit	
Tae H. Yoon	1714	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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